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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/689,262	10/20/2003	Min-Chieh Chou	64,600-126	2887	
7590 08/11/2004			EXAM	EXAMINER	
TUNG & ASSOCIATES			NGUYEN, JIMMY		
Suite 120	alsa D and		ART UNIT	PAPER NUMBER	
838 W. Long Lake Road Bloomfield Hills, MI 48302			2829		

DATE MAILED: 08/11/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

t) in		. <b>N</b>
	Application No.	Applicant(s)
Office Action Commons	10/689,262	CHOU ET AL.
Office Action Summary	Examiner	Art Unit
	Jimmy Nguyen	2829
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence address
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be ting within the statutory minimum of thirty (30) day will apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	nely filed s will be considered timely. the mailing date of this communication. D (35 U.S.C. § 133).
Status		
<ul> <li>1) Responsive to communication(s) filed on 20 December 2a) This action is FINAL.</li> <li>2b) This 3) Since this application is in condition for alloware closed in accordance with the practice under Expression 1.</li> </ul>	action is non-final. nce except for formal matters, pro	
Disposition of Claims		
4) ☐ Claim(s) 1-20 is/are pending in the application. 4a) Of the above claim(s) is/are withdraw 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1-20 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or	vn from consideration.	
Application Papers		
9)⊠ The specification is objected to by the Examine 10)⊠ The drawing(s) filed on 20 October 2003 is/are: Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11)□ The oath or declaration is objected to by the Ex	a)⊠ accepted or b)⊡ objected drawing(s) be held in abeyance. Se ion is required if the drawing(s) is ob	e 37 CFR 1.85(a). jected to. See 37 CFR 1.121(d).
Priority under 35 U.S.C. § 119		
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority document: 2. Certified copies of the priority document: 3. Copies of the certified copies of the priority application from the International Bureau * See the attached detailed Office action for a list	s have been received. s have been received in Applicat rity documents have been receive u (PCT Rule 17.2(a)).	ion No ed in this National Stage
Attachment(s)	_	
<ol> <li>Notice of References Cited (PTO-892)</li> <li>Notice of Draftsperson's Patent Drawing Review (PTO-948)</li> <li>Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)</li> <li>Paper No(s)/Mail Date</li> </ol>	4)  Interview Summary Paper No(s)/Mail D 5)  Notice of Informal F 6)  Other:	

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### **DETAILED ACTION**

## Specification

- Page 13 lines 2 and 3, probe pin "36" instead of "83"

## Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 2. Claims 1 4, 7 10, 12 19 are rejected under 35 U.S.C. 102(e) as being anticipated by Mathieu et al. (US 6616966).

As to claims 1, 13, Mathieu et al disclose (figs 23 – 26) a probe module comprising:

a probe base (730A, 730B);

a plurality of probe pins (760A, 760B) each having a generally tetrahedral probe ti carried by said probe base (730A, 730B); and

a circuit interconnect device (486, fig 23) for connecting said plurality of probe pins (760A, 760B) to an inspection apparatus.

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As to claims 2, 4, 8, 10, 14, 16, 18, Mathieu et al disclose (figs 23 – 26) the probe module of claim 1 wherein each of said plurality probe pins (760A, 760B) comprises a probe pin body (740A, 740B), a probe pin head (760A, 760B) carried said probe pin body (740A, 740B) and generally tapered probe pin tip (760A, 760B) provided on said probe pin head.

As to claims 3, 9, 12, 15, Mathieu et al disclose (figs 23 – 26) the probe module of claim 1 wherein said circuit interconnect device (480, fig 23) comprises a plurality of conductive probe circuits (486) provided on said probe base (730A, 730B) in electrical contact with said plurality of probe pins (760A, 760B), respectively, and a flexible circuit board (480) provided in electrical contact with said plurality of conductive probe circuits (486).

As to claims 7, 17, Mathieu et al disclose (figs 23 – 26) a compression arm (the upper portion of the board 480) carried by probe base and engaging plurality of probe pins (471).

As to claim 19, Mathieu et al disclose (figs 23 – 26) the probe pin tip (760A, 760B) has a generally polyhedral configuration.

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## Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
  - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claims 5, 6, 11, 20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Mathieu et al. (US 6616966) in view of Di Stefano (US 6771084).

As to claims 5, 11, 20, Mathieu et al disclose everything except for the probe module wherein each of plurality of said a probe pin body, a probe pin head carried by said probe pin body and a generally semi-spherical probe pin provided on said probe pin head.

On the other hand, Di Stefano teach the probe module (fig 13C) wherein each plurality of said a probe pin body (282), a probe pin head (281) carried by said probe pin body (282) and a generally semi-spherical probe pin provided on said probe pin head.

It would have been obvious to one having an ordinary skill in the art at the time of the invention was made to modify the probe pin head with a semi-spherical shape for the purpose of contacting noble metal contact pads (column 9 lines 55 - 57).

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As to claim 6, Mathieu et al disclose (figs 23 – 26) the probe module of claim 1 wherein said circuit interconnect device (480, fig 23) comprises a plurality of conductive

probe circuits (486) provided on said probe base (730A, 730B) in electrical

contact with said plurality of probe pins (760A, 760B), respectively, and a flexible circuit

board (480) provided in electrical contact with said plurality of conductive probe circuits

(486).

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jimmy Nguyen at (571) 272- 1965. Any inquiry of a general nature of relating to the status of this application or proceeding should be directed to the Group receptionist whose telephone number is (703) 305-4900.

JN.

August 4, 2004

DAVID ZARNEKE

PRIMARY EXAMINER